

5. Quick reference data

Table 2: Quick reference data

Symbol	Parameter	Conditions	Typ	Max	Unit
V_{DRM}	repetitive peak off-state voltage				
	MAC97A8	$T_j = 25 \text{ to } 125^\circ\text{C}$	–	600	V
	MAC97A6	$T_j = 25 \text{ to } 125^\circ\text{C}$	–	400	V
$I_{T(RMS)}$	on-state current (RMS value)	full sine wave; $T_{lead} \leq 50^\circ\text{C}$; Figure 5	–	0.6	A
I_{TSM}	non-repetitive peak on-state current		–	8.0	A

6. Limiting values

Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage				
	MAC97A8	$T_j = 25 \text{ to } 125^\circ\text{C}$	–	600	V
	MAC97A6	$T_j = 25 \text{ to } 125^\circ\text{C}$	–	400	V
$I_{T(RMS)}$	on-state current (RMS value)	full sine wave; $T_{lead} \leq 50^\circ\text{C}$; Figure 5	–	0.6	A
I_{TSM}	non-repetitive peak on-state current	full sine wave; $T_j = 25^\circ\text{C}$ prior to surge			
		$t = 20 \text{ ms}$	–	8.0	A
		$t = 16.7 \text{ ms}$	–	8.8	A
I^2t	I^2t for fusing	$t = 10 \text{ ms}$	–	0.32	A^2s
dI_T/dt	repetitive rate of rise of on-state current after triggering	$I_{TM} = 1.0 \text{ A}$; $I_G = 0.2 \text{ A}$; $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$			
		$T2+ G+$	–	50	$\text{A}/\mu\text{s}$
		$T2+ G-$	–	50	$\text{A}/\mu\text{s}$
		$T2- G-$	–	50	$\text{A}/\mu\text{s}$
		$T2- G+$	–	10	$\text{A}/\mu\text{s}$
I_{GM}	gate current (peak value)	$t = 2 \mu\text{s}$ max	–	1	A
V_{GM}	gate voltage (peak value)	$t = 2 \mu\text{s}$ max		5	V
P_{GM}	gate power (peak value)	$t = 2 \mu\text{s}$ max	–	5	W
$P_{G(AV)}$	average gate power	$T_{case} = 80^\circ\text{C}$; $t = 2 \mu\text{s}$ max	–	0.1	W
T_{stg}	storage temperature		–40	+150	$^\circ\text{C}$
T_j	operating junction temperature		–40	+125	$^\circ\text{C}$

7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-lead)}$	thermal resistance from junction to lead	full cycle	60	K/W
		half cycle	80	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed circuit board; lead length = 4 mm; Figure 1	150	K/W

7.1 Transient thermal impedance

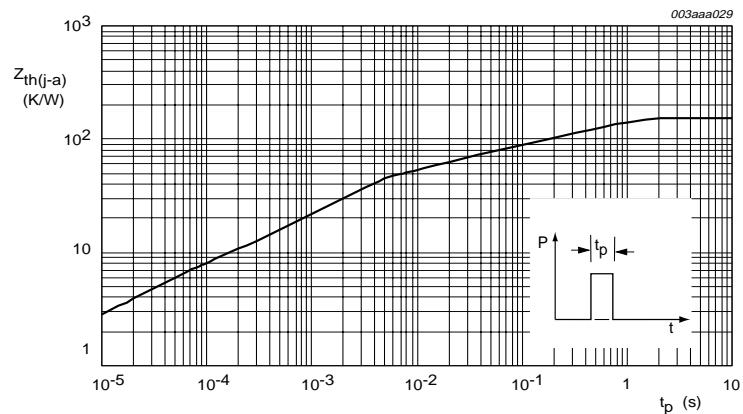


Fig 1. Transient thermal impedance from junction to ambient as a function of pulse duration.

8. Characteristics

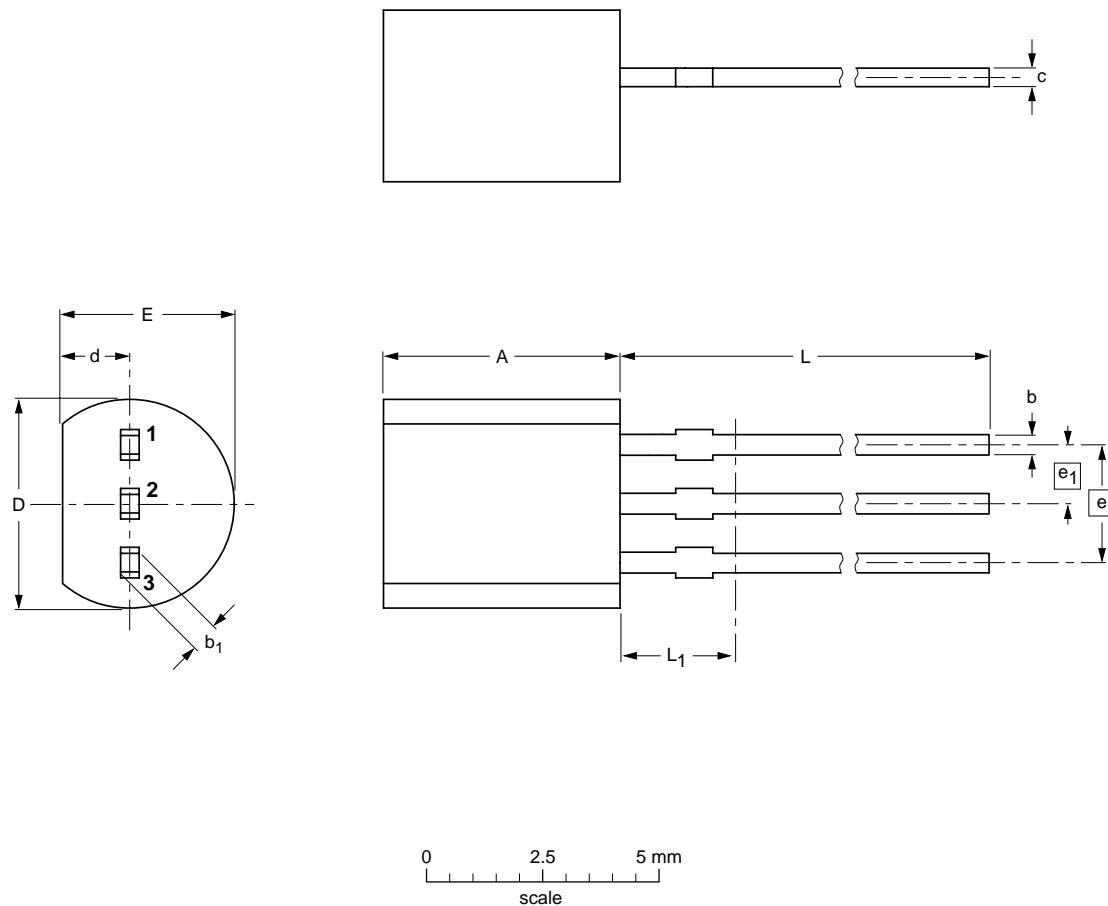
Table 5: Characteristics $T_j = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
I_{GT}	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$; Figure 8				
		T2+ G+	–	1	5	mA
		T2+ G–	–	2	5	mA
		T2– G–	–	2	5	mA
		T2– G+	–	4	7	mA
I_L	latching current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$; Figure 9				
		T2+ G+	–	1	10	mA
		T2+ G–	–	5	10	mA
		T2– G–	–	1	10	mA
		T2– G+	–	2	10	mA
I_H	holding current	$V_D = 12 \text{ V}; I_{GT} = 0.1 \text{ A}$; Figure 10	–	1	10	mA
V_T	on-state voltage	$I_T = 0.85 \text{ A}$; Figure 11	–	1.4	1.9	V
V_{GT}	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}$; Figure 7	–	0.9	2	V
		$V_D = V_{DRM}$; $I_T = 0.1 \text{ A}$; $T_j = 110^\circ\text{C}$	0.1	0.7	–	V
I_D	off-state leakage current	$V_D = V_{DRM(\max)}$; $T_j = 110^\circ\text{C}$	–	3	100	μA
Dynamic characteristics						
dV_D/dt	critical rate of rise of off-state voltage	$V_D = 67\%$ of $V_{DM(\max)}$; $T_{case} = 110^\circ\text{C}$; exponential waveform; gate open circuit; Figure 12	30	45	–	$\text{V}/\mu\text{s}$
dV_{com}/dt	critical rate of rise of commutation voltage	$V_D = \text{rated } V_{DRM}$; $T_{case} = 50^\circ\text{C}$; $I_{TM} = 0.84 \text{ A}$; commutating $dI/dt = 0.3 \text{ A/ms}$	–	5	–	$\text{V}/\mu\text{s}$
t_{gt}	gate controlled turn-on time	$I_{TM} = 1.0 \text{ A}$; $V_D = V_{DRM(\max)}$; $I_G = 25 \text{ mA}$; $dI_G/dt = 5 \text{ A}/\mu\text{s}$	–	2	–	μs

9. Package outline

Plastic single-ended leaded (through hole) package; 3 leads

SOT54



DIMENSIONS (mm are the original dimensions)

UNIT	A	b	b ₁	c	D	d	E	e	e ₁	L	L ₁ ⁽¹⁾
mm	5.2 5.0	0.48 0.40	0.66 0.56	0.45 0.40	4.8 4.4	1.7 1.4	4.2 3.6	2.54	1.27	14.5 12.7	2.5

Note

1. Terminal dimensions within this zone are uncontrolled to allow for flow of plastic and terminal irregularities.

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	EIAJ			
SOT54		TO-92	SC-43			97-02-28

Fig 13. SOT54 (TO-92).